

REMARKS

Applicants request that the Examiner enter the amendment prior to examining the application. In the specification, paragraphs [0016], [0028], [0035], [0036], [0040], [0041], [0044], [0045], [0054], [0056], and [0063] have been amended to correct informalities. Claims 1-7, 15, 17-27, and 29-33 have been amended. These amendments are not presented to distinguish a reference, thus, the claims as amended are entitled to a full range of equivalents if not previously amended to distinguish a reference. In the drawings, Figure 1 has been amended to include previously omitted element label 100. Applicants believe that this amendment does not introduce new matter. Entry of the amendment is respectfully requested.

Respectfully submitted,


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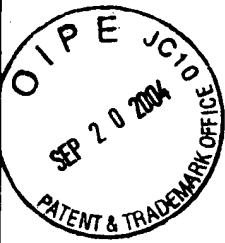
In the Drawings:

The attached sheet of drawings includes changes to Figure 1 and replaces the original sheet including Figure 1.

In Figure 1, previously omitted element label 100 has been inserted.

Attached is 1 sheet of formal drawings showing the abovementioned change and a marked-up copy of the original sheet. Please amend and admit Figure 1 as shown in the attached sheet.

Attachment: **Replacement Sheet**
 Annotated Sheet Showing Change



ATTY DKT. NO.: ANNOTATED SHEET
U.S. SERIAL NO.: AMAT/8327/ETCH/SILICON/JB
FILED: 10/690,318 CONFIRMATION: 1763
APPLICANT: October 21, 2003
TITLE: APPLIED MATERIALS, INC.
INVENTOR: Method for Controlling Accuracy and Repeatability of an Etch Process
Mul, et al.

FIGURE 1

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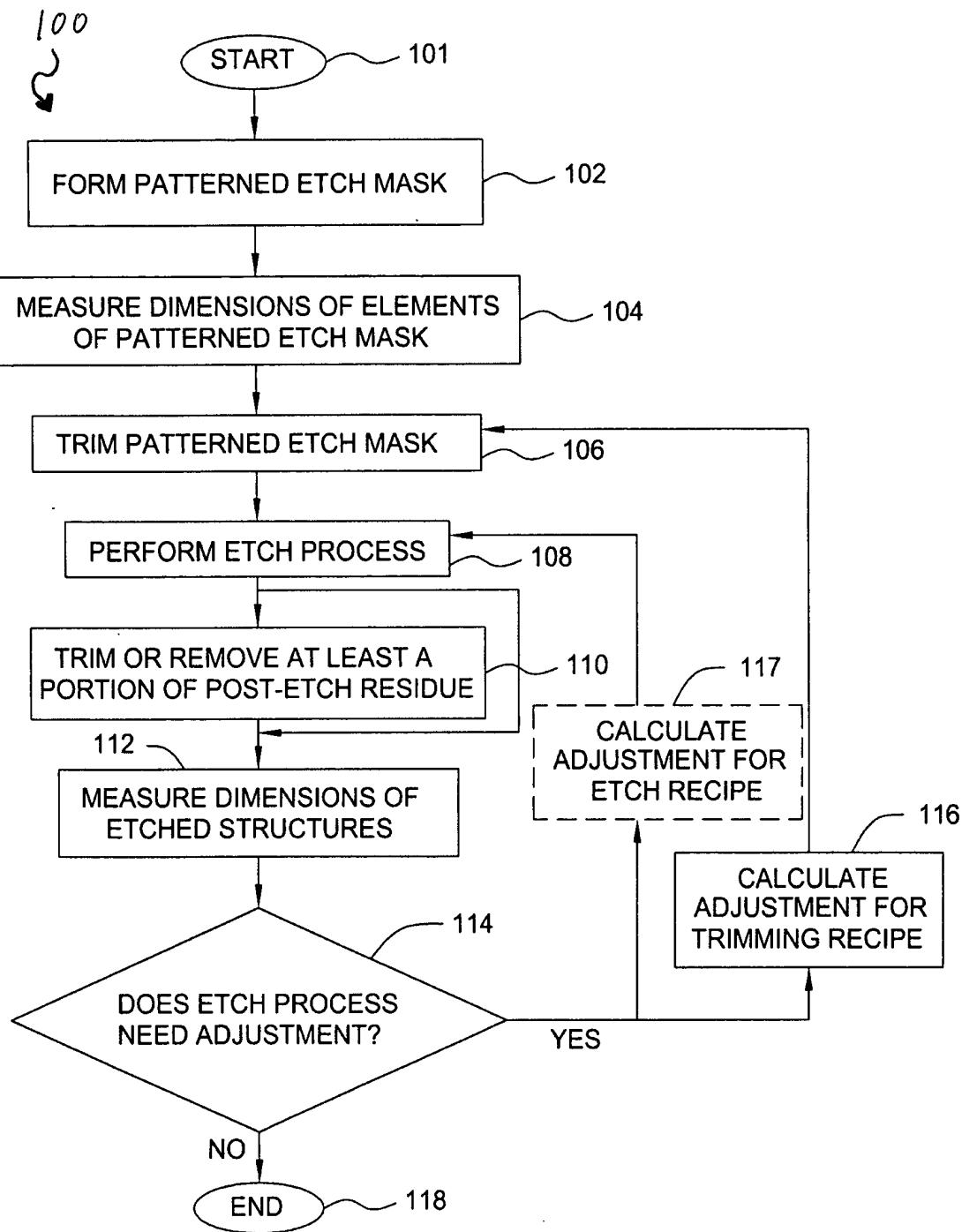


FIG. 1